

Notice of References Cited

Application/Control No.

10/790,168

Applicant(s)/Patent Under
Reexamination
SOBCHAK ET AL.

Examiner

Siu M. Lee

Art Unit

2611

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0050987 A1	12-2001	Yeap et al.	379/399.01
*	B	US-6,115,614	09-2000	Furukawa, Hiroshi	455/525
*	C	US-6,192,067 B1	02-2001	Toda et al.	375/144
*	D	US-6,426,983 B1	07-2002	Rakib et al.	375/346
*	E	US-2004/0008765 A1	01-2004	Chung et al.	375/233
*	F	US-2002/0006174 A1	01-2002	Nafie et al.	375/346
*	G	US-7,092,352 B2	08-2006	Shattil, Steve J.	370/210
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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